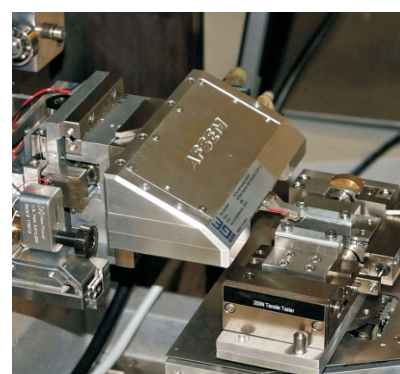
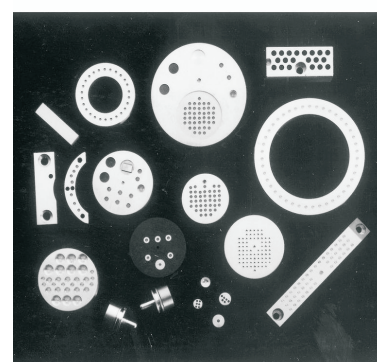
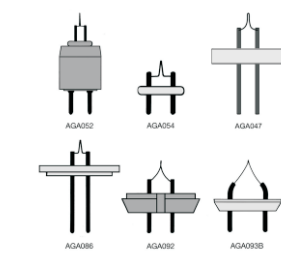


电子显微镜配套设备及耗材 Grids / Support films substrates / Tweezers and small tools / Vacuum coating and evaporation materials / Diamond knives

FIB accessories / Filaments and apertures / Consumables kit



上海禾早电子科技有限公司

电话 021-59805057

E-mail lfpaul@163.com

www.mricohezao.com

Agar Scientific has established an excellent reputation as a leading international supplier of scientific instruments and accessories for over 40 years, specialising in consumables and equipment for all forms of microscopy.

The Agar Scientific servicing team has skilled, certified service engineers who supply, maintain and repair instrumentation and equipment across a range of Electron Microscopy related fields, helping academic institutions and commercial labs across the UK and Europe to keep their equipment operational.

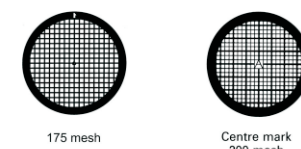


part Of Thermo Fisher Scientific

Agar耗材选型手册

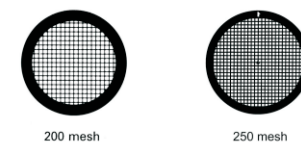
TEM耗材

Standard pattern

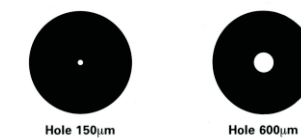


尺寸: 3.05mm

材质: 铜、镍、金、铂



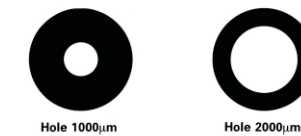
型号: 50mesh、75mesh
150mesh、200mesh
300mesh、400mesh



Hole grids

尺寸: 3.05mm

材质: 铜、镍、金、铂



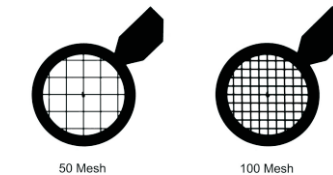
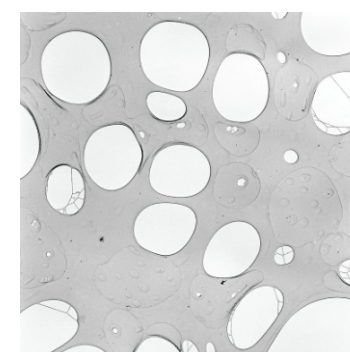
型号: 50μm、75μm
100μm、200μm
300μm、400μm
500μm、600μm
800μm、1000μm
1500μm、2000μm

Holey carbon films

孔径尺寸: 约100μm

材质: 铜、镍、金

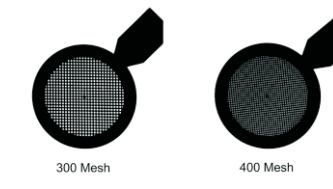
型号: 300mesh、400mesh
H7 finder grid



Tabbed grids

尺寸: 3.05mm

材质: 铜、镍、金

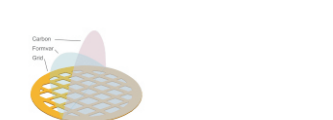


型号: 50mesh、100mesh
200mesh、300mesh
400mesh、500mesh
Slot mesh 300*75
Slot 2*1mm

SUPPORT FILMS FORMVAR CARBON

尺寸: 3.05mm

材质: 铜、镍、金

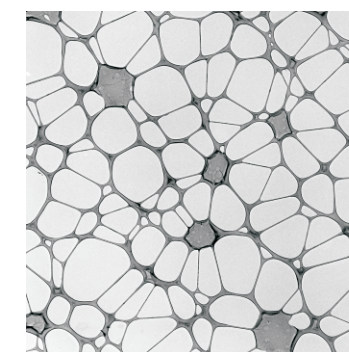


型号: 75mesh、100mesh
200mesh、300mesh
400mesh、slot 2*1mm
F1 finder grid
H7 finder grid

Lacey carbon films

材质: 铜、镍、金

型号: 300mesh、400mesh
H7 finder grids

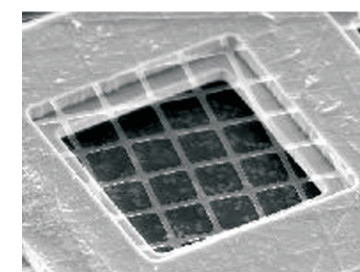


Square carbon frims

尺寸: 7*7μm

材质: 铜、镍、金

型号: 200mesh 300mesh
400mesh

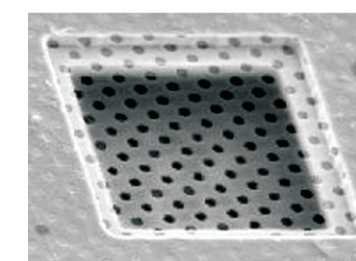


Circular carbon frims

尺寸:
1.2μm dia, sparation 1.3μm
2μm dia, sparation 2μm
1μm dia, sparation 4μm
2μm dia, sparation 1μm

材质: 铜、镍、金

型号: 200mesh、300mesh
400mesh



Grid storage boxes

型号: 50grids
96grids
100grids
50 tabbed grids



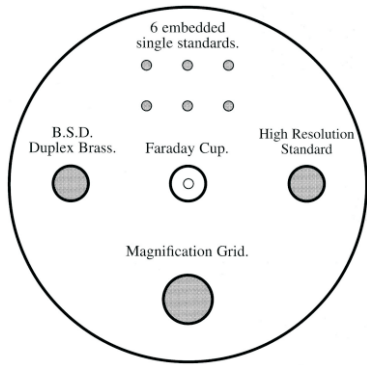
Cryo grid boxes

型号:
Cryo grid box with lid, round
Cryo grid box base only, round
Cryo grid box with lid, square
Cryo grid box handling rod



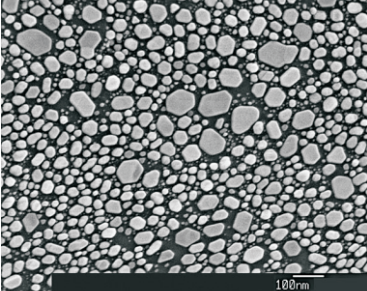
SEM/EDS标样

SEM多功能校准试样



功能:
6种EDS校准常用标样
BN, C, Mn, Co, Cu,
Mn3Al2Si3O12
B.S.D Duplex brass
Faraday Cup
High Resolution Standard
Magnification Grid

金颗粒标样



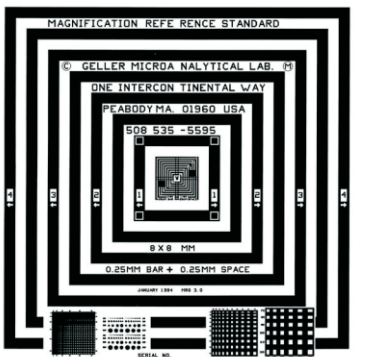
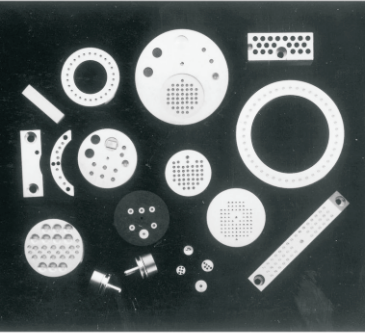
测试范围: 5-150nm

SEM型号:
JEOL、ZEISS
TESCAN、FEI
HITCHE

高真空仪器标样

仪器类型: SEM、EXCA、Auger electron probe

型号: 53种矿物质单质标样



标尺校准标样

支持仪器: OM、SEM、TEM
scanning probe
LSCM

校准范围: 10×-50000×

常用耗材

双面碳胶带



型号: 8mm×20m
12mm×20m
20mm×20m
50mm×20m

导电胶水



规格:
碳导电胶水
银导电胶水

进口冷镶嵌树脂



颜色: 无色、黑色
红色等

特点: 良好收缩比
无味无毒
固化时间可控
4-12H

Pon812生物环氧树脂套装



规格: 812树脂
DDSA硬化剂
NMA硬化剂
DMP-30催化剂

抛光砂纸



材质: 碳化硅、氧化铝
规格: P80、P120
P240、P320
P400、P600
P800、P1200
P2500、P4000

双面碳胶贴



型号: 9mm dia
12mm dia
25mm dia

金属导电胶带



规格: 铝、铜、银

型号:
6mm×55mm
12mm×55mm
25mm×55mm

进口冷镶嵌套装



规格: 环氧树脂
加固剂
量杯
模具

金刚石砂纸



划痕间隔:
30 μm、15 μm
9 μm、6 μm
3 μm、1 μm
0.5 μm、0.1 μm


玛瑙研钵



规格: 35×10mm
50×18mm
65×18mm


制样小工具

高精度无磁镊子




型号:
Strong, fine
flat tips
very flat tips
extra fine tips
Oblique
straight

高精度生物镊子




型号:
Extra fine, straight tips
super-fine, very fine
curved tips

高精度自锁镊子




型号:
fine tips, strong
flat, rounded tips
very fine tips,
curved tips

样品台专用镊子



型号: 1/2-3/8
1/4-3/8
1/8-3/16
10mm、15mm、
25mm、32mm


真空吸笔



类型: 电池式, 手动

规格: 3mm、5mm
7mm、10mm

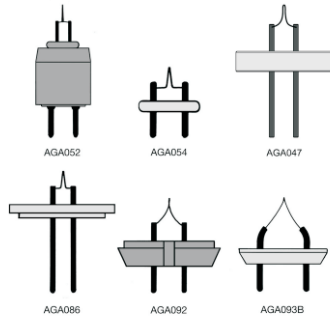
超薄切片金刚石刀具



型号: 25°、35°、45°
25nm-200nm
30nm-1 μm
0.2-5 μm

尺寸: 1.5mm、2mm
2.5mm、3mm
3.5mm、4mm

SEM钨灯丝



SEM钨灯丝

规格: 预对灯丝
未对灯丝

型号:TESCAN
ZEISS
FEI
HITCHE
JEOL



六硼化钨灯丝

规格: 90° cone 15µm microflat
90° cone 20µm microflat
60° cone 6µm microflat

型号: TESCAN
ZEISS
FEI
HITCHE
JEOL

离子溅射靶材



碳棒

规格: 6.3mm×150mm
3.05mm×300mm
4.6mm×300mm
6.15mm×300mm



碳绳

规格: 1.55g/m, 2.5mm dia, 3m
0.7g/m, 1.0mm dia, 1m
0.4g/m, 1.0mm dia, 1m
0.27g/m, 0.7m dia, 5m
Balzers/Bal-Tec, 3.5m

SEM/TEM样品台



TEM样品台底座



TEM样品台底座



进口金属靶材

材质: Au、Au/Pa、Pt
Pt/Pd、Ni、Ag
Cr等

规格: 57×0.1mm/0.2mm
54×0.1mm/0.2mm
58×0.1mm/0.2mm
40×0.1mm/0.2mm
115×0.1mm/0.2mm



国产金属靶材

材质: Au、Au/Pa、Pt
Pt/Pd、Ni、Ag
Cr等

规格: 57×0.1mm/0.2mm
54×0.1mm/0.2mm
58×0.1mm/0.2mm
40×0.1mm/0.2mm
115×0.1mm/0.2mm

FIB配件/耗材



样品台底座

规格:可接受定制



样品盒

规格: 样品台盒
高弹膜盒
钉子样品台盒等



包埋硅胶板

规格: 10 cavities
20 cavities
21 cavities
24 cavities
28 caities



钉型样品台

规格: 9.5mm
45/90° 45°
70°、45/90°



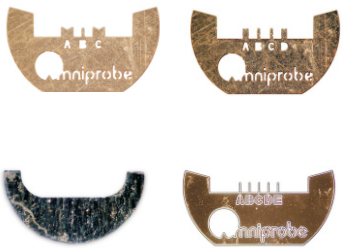
钉型样品台

规格: 12.7mm
36°、38°
90°



圆弹簧夹片样品台

规格: 平面
30°、45°
60°、90°



FIB铜网

规格: half-ring
3 post
4 post
5 post



M-Bond 610
离子减薄胶水套装

规格:resin(14g)
agent(11g)



抛光膏

规格:250g



FIB探针

材质: 钨

规格: tip radius<0.5µm
10-13° /6° taper angle



三角抛光器

规格:590 Kid for SEM
590+ Kit for SEM+TEM
590S Kit for TEM



金刚石悬浮液

规格: 0.1µ, 0.25µ
1.0µ, 3.0µ
5.0µ, 6.0µ
9.0µ, 15.0µ
30.0µ and 45.0µ

SEM/TEM制样设备

电镜相关设备

离子溅射仪

Agar auto sputter coater
Pumping system
Film thickness monitor
Chamber size:120*120mm



喷碳仪

Agar auto carbon coater
Pumping system
Film thickness monitor
Chamber size:120*120mm

金刚石慢速切割机

4" (100mm) diameter
diamond saw
6" (150mm) diameter
diamond saw



亲水化处理仪

Precise and easy vacuum setting
Short cycle times
Consistent results
Auto, programmed and manual mode
Intuitive touch screen for display and operation
Supports hydrophilic/hydrophobic and negative/positive modes
Affordable, compact standalone system
L-Gasket protects glass jar at base

自动抛光仪



电解抛光腐蚀仪

电压、电流范围大，可同时满足各种材料的抛光和腐蚀；
实现恒定电流和恒定电压工作方式；可控制样品的抛光/腐蚀面积，从而保证样品的抛光/腐蚀电流稳定；控制抛光/腐蚀时间；
搅拌装置保证了抛光/腐蚀介质均匀，样品表面环境一致；
工作电压、电流可输入计算机，以便于进一步数据分析和研究。

消磁系统

Magnetic field cancelling systems provide an effective solution for dampening ambient magnetic fields, allowing high resolution performance of TEM, SEM and FEG SEM instruments. The system comprises of a magnetic field control unit, magnetic field sensor and three multicore cables. The cables are installed in the room on the X, Y and Z axes. The sensor measures the strength and phase of the field in real time. The signals are fed to the control unit where three power amplifiers drive anti-phase currents through the multicore cables to effectively nullify the field.



冷冻干燥仪

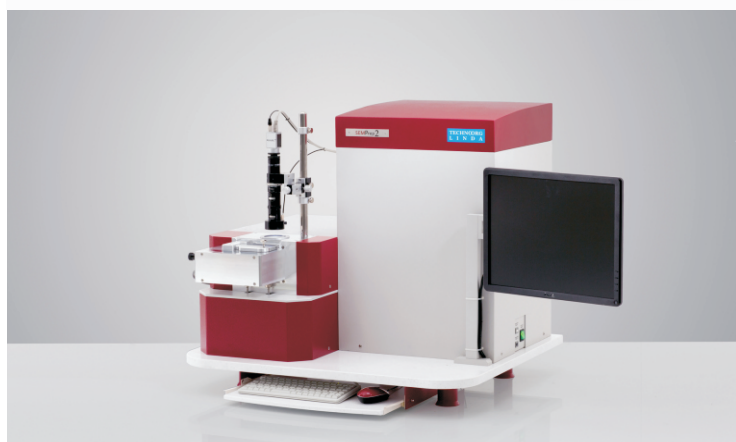
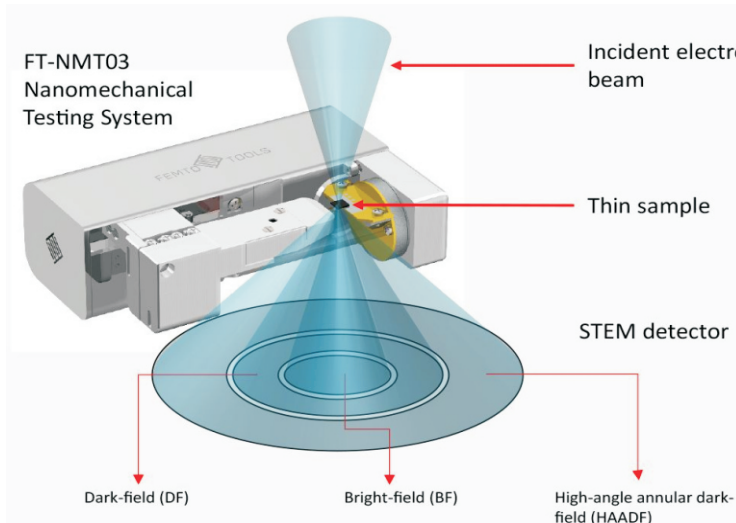
Simple robust construction - easy to maintain.
Horizontal chamber and large viewing window - excellent visibility of the fluid level and drying process.
Large robust valves for draining fluids, ingress of CO2 and venting of gas - very durable; the rapid ingress of CO2 helps prevent pre-drying of specimens



精密切割机



红外烘烤灯



EPHEMERON LABS INS 电子束感应电流 ELECTRON BEAM INDUCED CURRENT (EBIC) IMAGING SYSTEMS

We can provide you with a custom solution of hardware and software accessories to make EBIC measurements possible on your SEM. With femtoampere sensitivity, we make it easier to probe current signals that are not accessible with other imaging systems. We do this by providing complete solutions from the most sensitive preamplifier, sample interfacing and shielding, and a purpose designed scan controller with highest resolution possible. All this adds up to measuring very small signals with unprecedented accuracy and very low noise.

FEMTO TOOLS

FT-NMT03

原位纳米力学性能测试系统

能同时实现SEM/FIB高分辨成像和纳米力学性能测试
力学测量范围0.5nN-200mN(9个数量级)
位移测量范围0.05nm-21mm(9个数量级)
能同时实现SEM/FIB高分辨成像和纳米力学性能测试
能在SEM/FIB最佳工作距离下实现高分辨成像(可达4mm)以及FIB切割和沉积
五轴(X,Y,Z,旋转,倾斜)位移记录器实现样品台上多样品的自动测试和扫描
导电的微力传感探针可有效减少荷电效应
能够通过力和位移两种控制模式实现各种力学测试,例如拉伸、压缩、弯曲、剪切、循环和断裂测试等
电性能测试模块能够实现力学和电学性能同步测试(样品座配备6个电极)
实现力学性能测试与其他SEM/FIB原位分析手段联用,如EDX、EBSD、离子束沉积和切割
五轴(X,Y,Z,旋转,倾斜)闭环控制保证样品和微力传感探针的精确对准

LinDa 离子减薄仪

SEMPREP2

High-quality site-specific sample preparation in SEM application

focused high-energy ion gun operating from up to 10 keV or optionally ultra high-energy ion gun operating up to 16 keV
focused low-energy ion gun in the range of 100 eV to 2 keV continuously and independently adjustable milling energy
beam current density: max. 100mA/cm² for focused high-energy ion gun
max. 150mA/cm² for ultra high-energy ion gun
max. 10mA/cm² for focused low-energy ion gun
sputtering rate: 150 µm/hour on Si at 30° for focused high-energy ion gun
550 µm/hour on Si at 30° for ultra high-energy ion gun
28 µm/hour on Si at 30° for focused low-energy ion gun

ACCURION主动减震台

型号: Sandwich_1000-4.0
Sandwich_1000-6.0
Sandwich_1000-8.0

应用领域:
AFM, STM
SEM, FE-SEM
UHV-STM
纳米力学探针
共聚焦显微术
激光扫描显微镜
光学轮廓仪
显微硬度检测仪等



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